

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV.7-80) PATENT AND TRADEMARK OFFICE					Atty. Docket No. GB 000180		Serial No.								
					Applicant PAUL F. FEWSTER et al.										
					Filing Date CONCURRENTLY		Group								
<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)															
<b>U.S. PATENT DOCUMENTS</b>															
Ex. Int.		Document Number						Date	Name	Class	Sub- class	Filing Date If Approp.			
	AA														
	AB														
	AC														
	AD														
	AE														
	AF														
<b>FOREIGN PATENT DOCUMENTS</b>															
		Document Number						Date	Country	Class	Sub- class	Trans.			
													Yes	No	
ACH	AG	0	3	1	8	0	1	2	A	2	5/31/89	EUROPE	G01N	23/207	X
ACH	AH	A	0	1	2	7	0	6	5	0	10/27/89	Japan (Abstract)	G01N	23/207	X
ACH	AI	A	0	1	2	7	6	0	5	2	11/6/89	Japan (Abstract)	G01N	23/207	X
	AJ														
	AK														
<b>OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)</b>															
ACH	AL	"Characterization of Thin Layers on Perfect Crystals with a Multipurpose High Resolution X-ray Diffractometer", Bartels, Journal Vacuum Science and Technology B Volume 1 page 338 (1983).													
	AM														
	AN														
Examiner <i>Allen C. Ho</i>										Date Considered <i>19 Oct 2004</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.															

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE										Atty. Docket No. GB000180		Serial No. 10/022,150	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)										Applicant Paul P. Fewster, et.al.			
										Filing Date December 13, 2001		Group 2882	

  

U.S. PATENT DOCUMENTS														
Ex. Int	AA	Document Number								Date	Name	Class	Sub-class	Filing Date If Approp.
ACH	AA	5	8	5	0	4	2	5	12/15/1998	Wilkins	378	85		
ACH	AB	5	8	7	8	1	0	6	3/2/1999	Fujiwara	378	79		
	AC													
	AD													
	AE													
	AF													

  

FOREIGN PATENT DOCUMENTS															
Ex. Int	AA	Document Number								Date	Country	Class	Sub-class	Trans.	
		Yes	No												
	AG														
	AH														
	AI														
	AJ														
	AK														

  

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)		
AL		
AM		
AN		

  

Examiner <u>Allen C Ho</u>	Date Considered <u>19 Oct. 2004</u>
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